

# **Process Qualification Report**

Reliability By Design

#### **Qualification Description:**

The information contained herein represents proof of Reliability and Performance of the baseline process technology listed below in accordance with the Qualification Plan and test methods referenced in Section 8.0, after exposure to a variety of environments (electrical, thermal, humidity, etc) and mechanical events that may occur during installation and operational lifetime of the product. Upon conclusion of the testing the product continued to operate within specification limits, demonstrating its capability of reliable operation throughout its lifetime.

The purpose of this report is to present Qualification Test results of the of referenced process technology. The Pericom product data presented in this report qualifies all products manufactured using the exact semiconductor materials and processing techniques used in the baseline process and its off-shoot processes. The report describes the qualification test program, procedures used, criteria enforced (at the time of product validation), and the resulting test data obtained during the Qualification Test. The materials and processing techniques used in the baseline process are incorporated into the off-shoot processes, so the quality/integrity of the baseline and off-shoots (i.e.: 2PxM, 1PxM) processes will be equivalent.

### Lot Background Information:

Qual Test Date:	Oct-214 updated Jun-2016	By Ext. Process:	0.09um 1P8M
Process Technology:	0.09um 1P8M (90nm)		0.90um 1PxM
Foundry & Code:	TSMC (T)		
Qual Test Number:	TN90CLQR002 QPE12010	Qual Vehicle:	TSMC part number PI7C9X2G304SLAFDE PI7C9X2G404SLBFDE ORM testing lots (various)
		Lot Numbers:	N6H511 00 NHA185 06 1

#### Pericom's Qualification Test Results:

Stress Test	Test Procedure	Test Conditions	Duration	# of Lots	Samples per Lot	Results Pass/Fail
Accelerated High Temp	JESD22-A108	1000 hrs 3.5V 1.2V(Core) 125°C	168 hrs	3	99	297 / 0
Operating Life		1000 hrs 3.5V 1.2V(Core) 125°C	500 hrs	3	99	297 / 0
(TSMC - AHTOL)		1000 hrs 3.5V 1.2V(Core) 125°C	1000 hrs	3	99	297 / 0
High Temp Operating	JESD22-A108	1000 hrs 1.2V 125°C	168 hrs	3	77	231 / 0
Life (HTOL)		1000 hrs 1.2V 125°C	500 hrs	3	77	231 / 0
(PI7C9X2G304SLA) (PI7C9X2G404SLB)		1000 hrs 1.2V 125°C	1000 hrs	3	77	231 / 0
	ELFR based on 528 units	ELF Rate (55C, 0.7 eV, 3.5V, 60% CL)	104			
	completed 168 hrs HTOL FIT based on 528 units completed 1,000 hrs HTOL	FIT Rate (55C, 0.7 eV, 3.5V, 60% CL)	20			
		Calculated MTBF (hours)	50,927,360			
Temp Cycle Test	JESD22-A104	-65°C to 150°C, 100cycles, 0V	200 cycles	3	77	231 / 0
	(Air to Air)	-65°C to 150°C, 100cycles, 0V	500 cycles	3	77	231 / 0
		-65°C to 150°C, 100cycles, 0V	1000 cycles	3	77	231 / 0
Temp Cycle Test	JESD22-A104	-65°C to 150°C, 100cycles, 0V	200 cycles	4	77	308 / 0
(ORM testing)	(Air to Air)	-65°C to 150°C, 100cycles, 0V	500 cycles	4	77	308 / 0
High Temp Storage	JESD22-A103	1000hrs, 0V, 150°C	168 hrs	3	77	231 / 0
(HTS)	MIL-STD-883, M1008	1000hrs, 0V, 150°C	500 hrs	3	77	231 / 0
		1000hrs, 0V, 150°C	1000 hrs	3	77	231 / 0
High Temp Storage	JESD22-A103	1000hrs, 0V, 150°C	168 hrs	4	77	308 / 0
(HTS)	MIL-STD-883, M1008	1000hrs, 0V, 150°C	500 hrs	4	77	308 / 0
(ORM testing)		1000hrs, 0V, 150°C	1000 hrs	4	77	308 / 0
Latch Up Test	EIA JESD78	Report available by Device				
ESD-HBM Test	JESD22-A114	Report available by Device				

#### Qualification by Extension Information:

It is valid to use the reliability data of a particular process technology and apply to all products within this process technology family. All parts within the same family are designed to the same rules (layout & electrical), and manufacturing is controlled by SPC. Within a product family, a device can only be fabricated on one process technology option.

If there are any questions about this qualification, please contact Quality Support at: <a href="mailto:customerquestion@pericom.com">customerquestion@pericom.com</a>

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Date:	Oct-214	updated Jun-2016

Subject: Pericom Process Qualification Report

Mfg-Fab-Process: TSMC (T) 0.09um 1P8M (90nm)

Qual Vehicle: TSMC part number, PI7C9X2G304SLAFDE, PI7C9X2G404SLBFDE

## By extension: Pericom active devices using the Fab/Process at the time of the Qualification:

PI7C9X2G303ELZXEX		
PI7C9X2G304ELZXAEX		
PI7C9X2G312GPNJE		
PI7C9X2G312GPNJEX		
PI7C9X2G404ELZXAEX		
PI7C9X2G606PRANJE		
PI7C9X2G606PRANJEX		
PI7C9X2G606PRBNJE		
PI7C9X2G606PRBNJEX		
PI7C9X2G608ELAZXAE		
PI7C9X2G608ELAZXAEX		
PI7C9X2G608ELZXAE		
PI7C9X2G608ELZXAEX		
PI7C9X2G608GPNJE		
PI7C9X2G608GPNJEX		
PI7C9X2G612GPANJE		
PI7C9X2G612GPANJEX		
PI7C9X2G612GPBNJE		
PI7C9X2G612GPBNJEX		
PI7C9X2G612GPNJE		
PI7C9X2G612GPNJEX		
PI7C9X2G303ELAZXE		
PI7C9X2G303ELAZXEX		
PI7C9X2G303ELBZXE		
PI7C9X2G303ELBZXEX		
PI7C9X2G304SLBFDE		
PI7C9X2G304SLBFDEX		
PI7C9X2G404SLBFDE		
PI7C9X2G404SLBFDEX		
PI7C9X2G304ELZXAE		
PI7C9X2G308GPNJE		
PI7C9X2G308GPNJEX		
PI7C9X2G312GPANJE		
PI7C9X2G312GPANJEX		
PI7C9X2G404ELZXAE		
PI7C9X2G608GPANJE		
PI7C9X2G608GPANJEX		
PI7C9X2G304SLAFDE		
PI7C9X2G304SLAFDEX		
PI7C9X2G404SLAFDE		
PI7C9X2G404SLAFDEX		

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